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TABLE OF CONTENTS

Instrumentation for X-ray Reflectivity in Micro Area: Present Status and Future Outlook	1
<i>Kenji Sakurai, Mari Mizusawa, Masashi Ishii, Shun-ichi Kobayashi, Yasuhiko Imai</i>	
The Importance to Reveal Buried Interfaces in the Semiconductor Heterostructure Devices	8
<i>Yoshikazu Takeda, Masao Tabuchi</i>	
Feasibility of Complementary Use of Neutron and X-ray Scattering Techniques in Research of Lipid Mixtures	14
<i>Mitsuhiro Hirai</i>	
Using Anomalous Dispersion Effect for Maximum Entropy Method Analysis of X-ray Reflectivity from Thin-film Stacks	21
<i>Kazuhiro Ueda</i>	
Structure Analysis of Amphiphilic Di-block Copolymer Monolayer by X-ray Reflectivity	27
<i>Takeshi Yamada, Sunyoung Jung, Hirohisa Yoshida</i>	
X-ray Diffraction Study on Self-organization of InAs Islands on GaAs(001)	31
<i>Masamitsu Takahashi, Jun'ichiro Mizuki</i>	
Depth Profile Analysis of Poly-crystalline Layers Structure and Crystal Grain Size Under Surface Using X-ray Diffraction at Small Glancing Angles of Incidence	36
<i>Yoshikazu Fujii, Takenori Nakayama</i>	
A Proposal of Depth Profile Analysis Method of Strain Distribution in Surface Layer Using X-ray Diffraction at Small Glancing Angles of Incidence	46
<i>Yoshikazu Fujii, Etsuya Yanase, Kozi Nishio</i>	
Oxidation Process Dependence of Strain Field Under the SiO₂/Si(001) Interface Revealed by X-ray Multiple-wave Diffraction	52
<i>W Yashiro, Y Yoda, K Takahashi, M Yamamoto, T Hattori, K Miki</i>	
Magnetic Structural Analysis of Magnetic Multilayers by Complementary Use of X-ray and Neutrons	58
<i>M Takeda, D Yamazaki, K Soyama, R Maruyama, M Hino, T Hirano</i>	
High-k Gate Dielectric Films Studied by Extremely Asymmetric X-ray Diffraction and X-ray Photoelectron Spectroscopy	61
<i>Yuki Ito, Koichi Akimoto, Hironori Yoshida, Takashi Emoto, Daisuke Kobayashi, Kazuyuki Hirose</i>	
X-ray Magnetic Circular Dichroism Studies for Fe/Si Interfaces Using Standing Waves	66
<i>Kosuke Sato, Masaki Sugawara, Takayoshi Jinno, Mitsunori Toyoda, Tadashi Hatano, Akira Arai, Mihiro Yanagihara</i>	

Interlayer Coupling in Epitaxial Co₂MnSi/X/Co₂MnSi (X=Cr and V) Trilayer Structures	72
<i>S Bosu, Y Sakuraba, K Saito, H Wang, S Mitani, K Takanashi</i>	
Application of X-ray Reflectivity Measurement to Monitoring of Chemical Reactions at 'buried' Interface	74
<i>Masashi Ishii, Aiko Nakao, Kenji Sakurai</i>	
Characterization of a Particle Size Distribution in a Ni-C Granular Thin Film by Grazing Incidence Small-angle X-ray Scattering	79
<i>Y Ito, K Inaba, K Omote</i>	
Effect of Osmotic Pressure on Ganglioside-cholesterol-DOPC Lipid Mixture	83
<i>Teruaki Onai, Mitsuhiro Hirai</i>	
Analysis of Multilayer Structure of Amphiphilic Di-block Copolymer by X-ray Reflectivity	89
<i>Takeshi Yamada, Sunyoung Jung, Hirohisa Yoshida</i>	
Coherent X-ray Diffraction Pattern of a SnZn Cast Alloy	93
<i>Y Takahashi, Y Nishino, T Ishikawa, E Matsubara</i>	
Development of the Total-reflection XAFS Method for the Liquid-liquid Interface	97
<i>Hajime Tanida, Hirohisa Nagatani, Makoto Harada</i>	
Development of Superlattice During Thermal Annealing in Pt/AlN Multilayer Films	101
<i>Takashi Harumoto, Ji Shi, Yoshio Nakamura</i>	
Curved Crystal X-ray Optics for a New Type of High Speed, Multiwavelength Dispersive X-ray Reflectometer	105
<i>Tadashi Matsushita, Yasuhiro Inada, Yasuhiro Niwa, Masashi Ishii, Kenji Sakurai, Masaharu Nomura</i>	
Small Angle X-ray Scattering Study on Effect of Replacement of Hydrogen Oxide (H₂O) by Deuterium Oxide (D₂O) on Anionic Phospholipid Bilayers	110
<i>Hiroshi Takahashi, Kazuki Ito</i>	
Structural Analysis for a Poly(methyl Methacrylate) Ultrathin Film in Water by Neutron Reflectivity	117
<i>Yoshihisa Fujii, Hironori Atarashi, Kei-ichi Akabori, Masahiro Hino, Keiji Tanaka, Toshihiko Nagamura</i>	
X-ray Reflection from a Water Surface Investigated by a New Liquid Interface Reflectometer at SPring-8	121
<i>Yohko F Yano, Tomoya Uruga, Hajime Tanida, Hidenori Toyokawa, Yasuko Terada, Masashi Takagaki</i>	
X-ray Analysis on the Size and Shape of J-aggregates Formed at the Air-water Interface	127
<i>Noritaka Kato</i>	
Thin-film Structure of Semiconducting End-capped Oligothiophenes	134
<i>N Yoshimoto, W Y Li, K Omote, J Ackermann, C Videlot-Ackermann, H Brisset, F Fages</i>	
Temperature-Dependent Change of Packing Structure of Condensed-Phase in a Micro-Phase Separated Langmuir Monolayer Studied by Grazing-Incidence X-ray Diffraction	139
<i>Ken-ichi Iimura, Teiji Kato, Gerald Brezesinski</i>	
In-Situ Reflectometry Observation on Structural Changes of Thin Self-Assembled Block Copolymer Films	144
<i>N Torikai, N L Yamada, D Kawaguchi, A Takano, Y Matsushita, E Watkins, J P Majewski, H Okuda</i>	

Observation of Reflected X-rays from End Face of Organic Thin Film	148
<i>Kouichi Hayashi, Tokujiro Yamamoto, Takahiro Nakamura, Kensuke Kitani, Kosuke Suzuki, Masahisa Ito, Hiromichi Adachi</i>	
One-dimensionally Curved Si and Ge Single Crystal Wafers Prepared by Hot-pressing: Potential Performance for Optical Components for X-ray Diffraction	153
<i>Hiroshi Okuda, Shojiro Ochiai, Kozo Fujiwara, Kazuo Nakajima</i>	
X-ray CTR Scattering Measurement to Investigate the Formation Process of InP/GaNAs Interface	159
<i>M Tabuchi, A Mori, Y Ohtake, Y Takeda</i>	
Study of Interfacial Structure of HfO₂ thin Film on Si by Grazing Incidence X-ray Reflectivity	163
<i>Lulu Zhang, Shin-ya Terauchi, Ruiqin Tan, Yasushi Azuma, Toshiyuki Fujimoto</i>	
Interdiffusion Studies for HfO₂/Si by GIXR and XPS	168
<i>Lulu Zhang, Shin-ya Terauchi, Yasushi Azuma, Toshiyuki Fujimoto</i>	
Soft X-ray Resonant Magnetic Reflectivity Study on Induced Magnetism in [Fe₇₀Co₃₀/Pd]_n Super-Lattice Films	173
<i>N Awaji, K Noma, K Nomura, S Doi, T Hirono, H Kimura, T Nakamura</i>	
Real-time Observation of Formation of Indium Phosphide Nanowires by Means of GISAXS	179
<i>T Kawamura, S Bhunia, S Fujikawa, Y Watanabe, J Matsui, Y Kagoshima, Y Tsusaka</i>	
Author Index	